Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/619,280	RIEKE ET AL.	
Examiner	Art Unit	
Anthony Weier	1761	

	SEAR	CHED	
Class	Subclass	Date	Examiner
435	293.2		
165	58, 64		
	120, 125		
	184	6/23/2006	AW
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74.0			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEAR((INCLUDING SE	CH NOTES EARCH STRATEGY)
	DATE	EXMR
Inventor Search	6/22/2006	AW